SPICE Device Model Si1419DH
Vishay Siliconix

P-Channel 200-V (D-S) MOSFET

CHARACTERISTICS

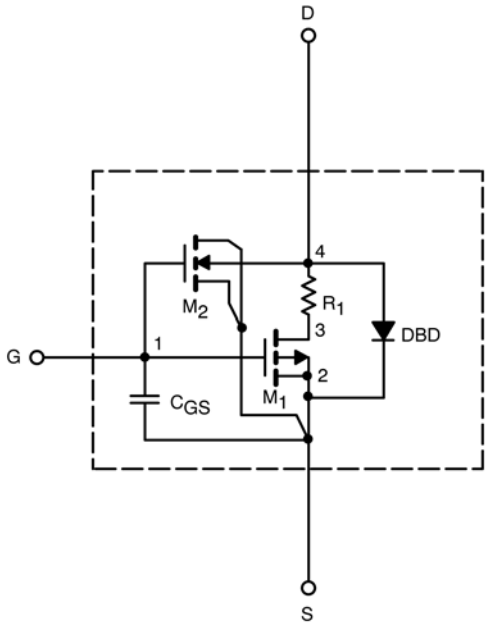
- P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the −55 to 125°C Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

DESCRIPTION

The attached spice model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit model is extracted and optimized over the −55 to 125°C temperature ranges under the pulsed 0-V to 10-V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

SUBCIRCUIT MODEL SCHEMATIC

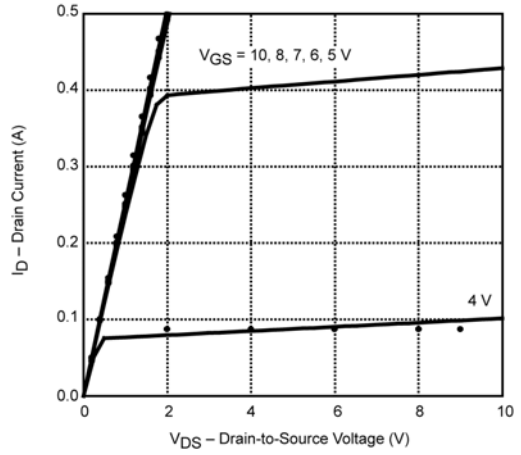


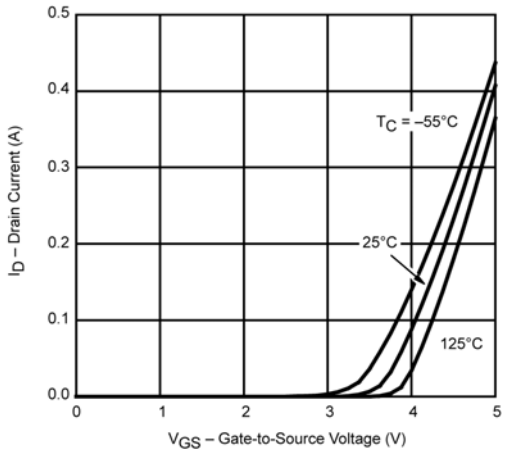
This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.

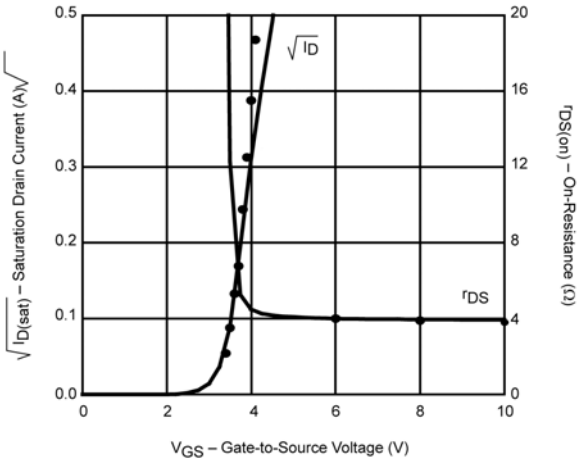
SPECIFICATIONS (T_J = 25°C UNLESS OTHERWISE NOTED)					
Parameter	**Symbol**	**Test Condition**	**Simulated Data**	**Measured Data**	**Unit**
Static					
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = –250 μA	3.1		V
On-State Drain Current [a]	$I_{D(on)}$	V_{DS} = –5 V, V_{GS} = –10 V	1.3		A
Drain-Source On-State Resistance [a]	$r_{DS(on)}$	V_{GS} = –10 V, I_D = –0.4 A	3.95	3.98	Ω
		V_{GS} = –6 V, I_D = –0.4 A	4.08	4.06	
Forward Transconductance [a]	g_{fs}	V_{DS} = –10 V, I_D = –0.4 A	0.5	1	S
Diode Forward Voltage [a]	V_{SD}	I_S = –0.4 A, V_{GS} = 0 V	–0.72	–0.80	V
Dynamic [b]					
Total Gate Charge	Q_g	V_{DS} = –100 V, V_{GS} = –10 V, I_D = –0.4 A	3.6	4.1	nC
Gate-Source Charge	Q_{gs}		0.8	0.8	
Gate-Drain Charge	Q_{gd}		1.3	1.3	

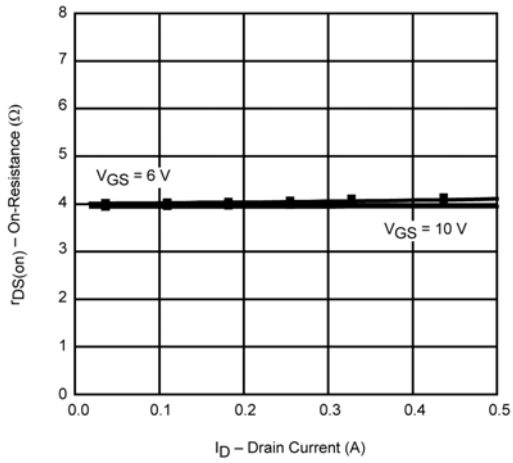
Notes
a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.
b. Guaranteed by design, not subject to production testing.

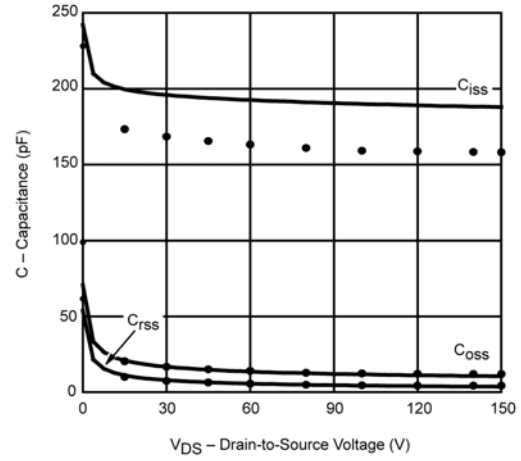
COMPARISON OF MODEL WITH MEASURED DATA (T_J=25°C UNLESS OTHERWISE NOTED)

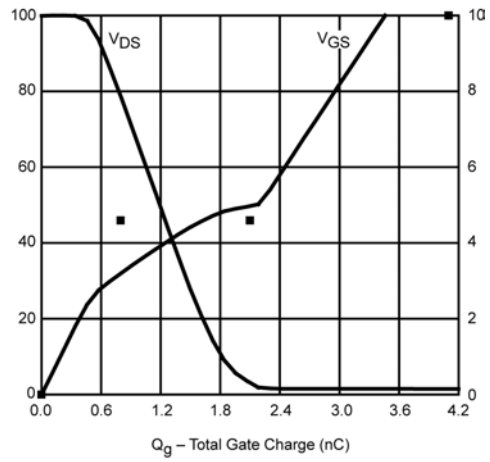












Note: Dots and squares represent measured data.